

# **Fabrication Basics**





**Optical Images:** [A] Graphene 60x [B] Graphene 20x [C] Graphene 60x











## **Custom Transfer Microscope**



The transfer microscope takes two different layers of material and contacts them together via a multi-step polymer adhesion process. The Gabor group currently characterizes by atomic force microscopy, Raman spectroscopy, and photoluminescence spectroscopy. These characterization techniques will ultimately inform experiments that probe the novel optoelectronics properties of MoTe<sub>2</sub>.









Graphene is the easiest semiconducting material to exfoliate. Various methods of mechanical exfoliation are employed to accommodate various crystal lattice structures. Graphene is cheaper and more abundant than synthetic TMD semiconductors in the bulk crystal form. Substrates are always placed into clean chip carriers to prevent cross-contamination. Pictures of ideal flake specimens are shown.



![](_page_0_Picture_26.jpeg)

devices capable of withstanding further characterization. Terraced TMD optical samples are especially of interest.

Fime delay  $\Delta t$  (ps) Massicotte, M. Nature Nanotechnology, 11(1), p. 42-46. (2015) Suveon, C. Science, 349(6248), p. 625-648, (2015)